Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/003,358	CHANG, FANG-CHENG
Examiner	Art Unit

Sun J. Lin

2825

SEARCHED					
Class	Subclass	Date	Examiner		
716	5	6/7/2005	JSL		
716	19	6/7/2005	JSL		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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716	19	6/7/2005	J3L	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (USPAT;US- PGPUB;UPO;JPO;DERWENT;IBM_T DB)	6/7/2005	JSL
IEEE	6/8/2005	JSL
IEEE	6/10/2005	JSL
GOOGLE	6/8/2005	JSL
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